Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination SHIMIZU ET AL.	
10/541,327		
Examiner	Art Unit	
Nauven N. Hanh	2924	

					
	SEARCHED				
Class	Subclass	Date	Examiner		
310	156.01- 158.84	6/20/2006	HN		
310	261	6/20/2008	HN		
310	262	6/20/2006	HN		
310	218	6/20/2008	HN		
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INTERFERENCE SEARCHED				
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3/0	156.08	9/4/07	HN	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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